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Application No. 09773522	Prepared by	L. MKKEENES	Tracking Number	06000303
Examiner-GAU TAIBOT 1762	Date	9/5/04	Week Date	8/23/04
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a. Serial No.	f. Foreign Priority	k. Print Claim(s)	PTO-1449		
b. Applicant(s)	g. Disclaimer	I. Print Fig.	q. PTOL-85b		
c. Continuing Data	h. Microfiche Appendix	m. Searched Column	r. Abstract		
d. PCT	i. Title	n. PTO-270/328	s. Sheets/Figs		
e. Domestic Priority	j. Claims Allowed	o. PTO-892	t. Other		
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i. Appendix	
j. Amendments	
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Su	bstitute for Vote 1449A/	NA PARTY			Complete if Known	
	THA			Application Number	09/773,522	r.
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S	TATEMENT	T BY AF	PPLICANT	First Named Inventor	Paul A. Farrar	C'I
				Group Art Unit	N/A On	
(use as many sheets as necessary)		Examiner Name	Not Yet Assigned			
					M4065.0392/P392	· •

		OTHER PRIOR ART – NON PATENT LITERATURE DOCUMENTS	
Examiner Initials	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T
*	L	Solder Transfer Technique for Flip-Chip and Electronic Assembly Applications, Karl J. Puttlitz, et al., IEEE Transactions on Components, Packaging and Manufacturing Technology, Part C, Vol. 21, No. 3, July, 1998.	
	M	MicroJet Printing of Solder and Polymers for Multi-Chip Modules and Chip-Scale Packages, Donald J. Hayes et al., MicroFab Technologies, Inc., IMPAS '99.	
}	N	Self-Aligned Controlled Collapse Chip Connect (SAC4), L. Pfeiffer et al., J. Electrochem.  Soc.: Solid-State Science and Technology, November 1987.	
¥	0	Review of Flip Chip Bonding, Vincent C. Marcotte, et al., IBM East Fishkill Facility.	
۲	Р	Solder Jet Printing of Micropads and Vertical Interconnects, David B. Wallace, et al., www.microfab.com/paper/smta97/smta97.htm, (8/12/00).	
Ç	Q	Combination Process for Final Metal Lines and Metal Terminals, Research Disclosure, No. 34232, Kenneth Mason Publications Ltd., England (October 1992/753).	
1	R	Process for High Density of Chip Terminals on Large Wafers, Research Disclosure, 34625 Kenneth Mason Publications Ltd., England (February 1993/97).	1
¥	S	Key Process Controls for Underfilling Flip Chips, Alec J. Babiarz et al., Solid State Technology, 1997 by PennWell Publishing Company.	
5	T	Mark's Standard Handbook for Mechanical Engineers, Tenth Edition, Eugene A. Avallone, et al.	
14	כ	Flow of gases through tubes and orifices, David G. Worden, Scientific Foundations of Vacuum Technique, Saul Dushman.	Γ
λį	<b>&gt;</b>	Sorption of gases by "active" charcoal, silicates (including glasses), and cellulose, "Scientific Foundations of Vacuum Technique", J. Wiley and Sons (1962).	Γ
١٧	W	Electronic Materials Handbook, Vol. 1, Packaging, pages 301, 440.	1
15	X	Technology Challenges for Advanced Interconnects, James G. Ryan et al, Conference Proceedings ULSI XIII@1998 Materials Research Study.	T

Examiner B. TalboT	Date Considered	3/25/03
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<sup>\*</sup>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<sup>&</sup>lt;sup>1</sup>Unique citation designation number. <sup>2</sup>Applicant is to place a check mark here if English language Translation is attached